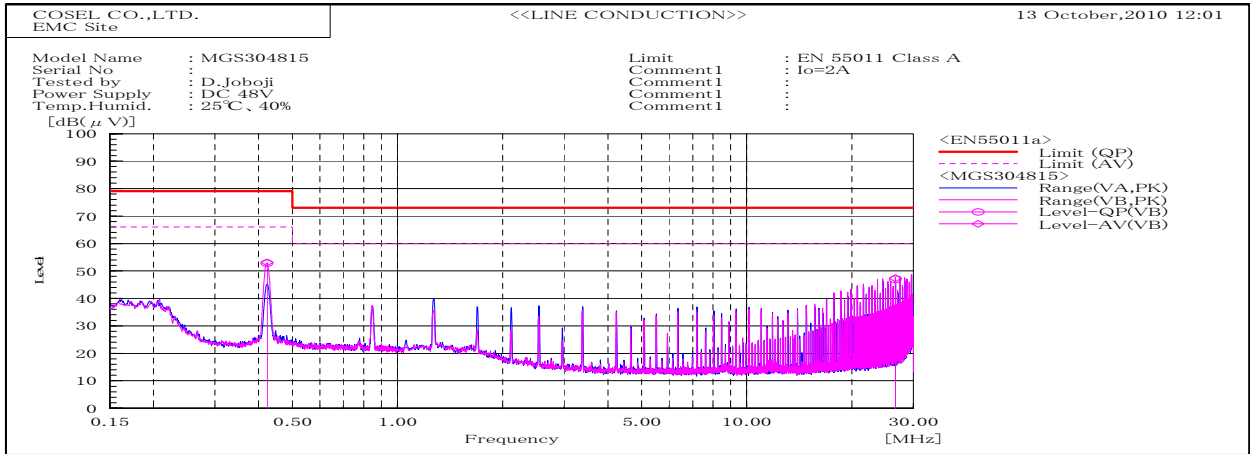
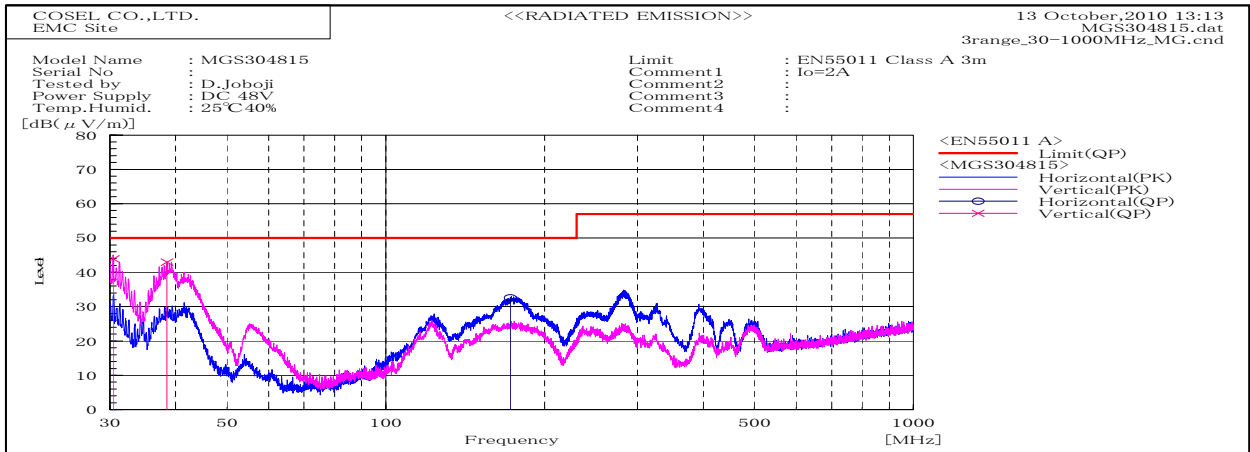


DATA SHEET			Date	19-Oct-10
Model	MGS304815		Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission		Humid.	40 %RH
			Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.42296		VB	42.8	43.1	10	52.8	53.1	79	66	26.2	12.9	Pass	
26.63715		VB	35.9	36.4	11	46.9	47.4	73	60	26.1	12.6	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
30.457	V	Stable	57.6	-13.7		43.9		50	6.1	100	267	
38.51	V	Stable	60.8	-17.8		43		50	7	102	349	
172.14	H	Stable	54.8	-22.2		32.6		50	17.4	159	27	

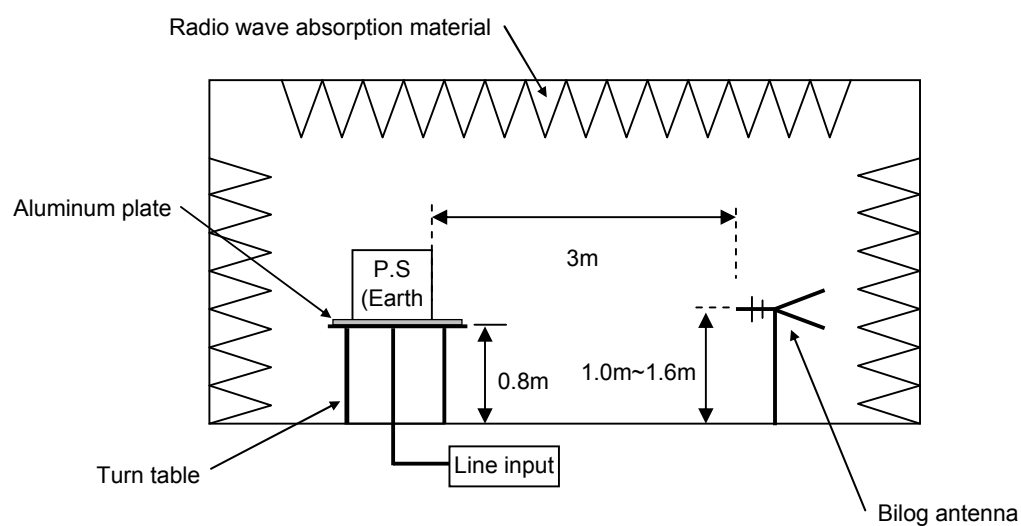
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

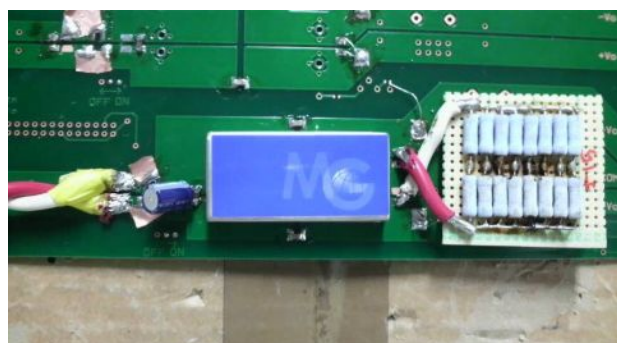


Conditions

Test : EMI
 Model Name : MGS3048□□/MGW3048□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

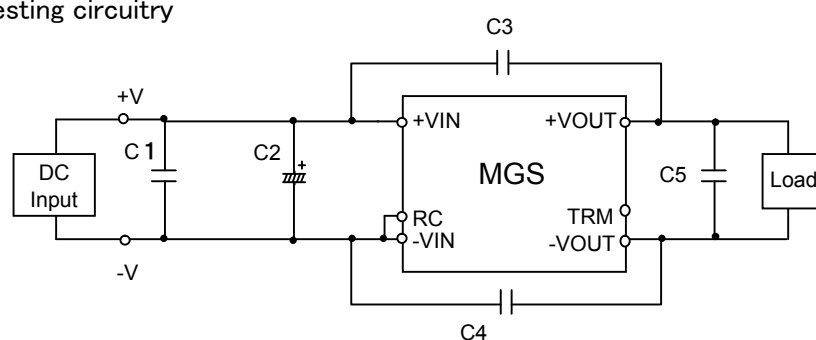


Fig.1 Testing circuitry 1

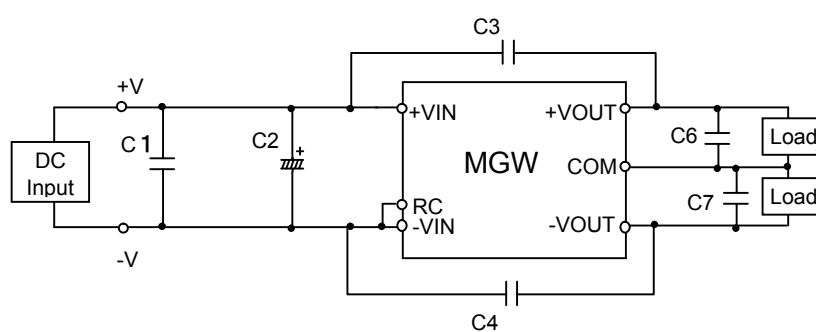


Fig.2 Testing circuitry 2

C1	:	100V	2.2 μ F	Ceramic Capacitor
C2	:	80V	47 μ F	Electrolytic Capacitor
C3,C4	:	2kV	1000pF	Ceramic Capacitor
C5,C6,C7	:	25V	22 μ F	Ceramic Capacitor